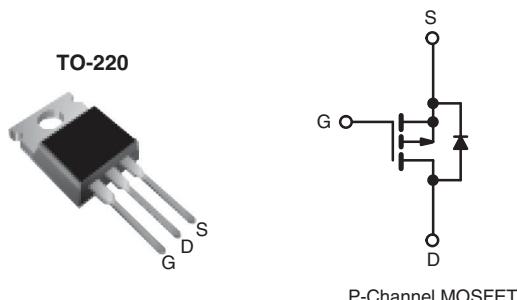


Power MOSFET

PRODUCT SUMMARY		
V _{DS} (V)	- 60	
R _{DS(on)} (Ω)	V _{GS} = - 10 V	0.28
Q _g (Max.) (nC)		19
Q _{gs} (nC)		5.4
Q _{gd} (nC)		11
Configuration	Single	



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- P-Channel
- 175 °C Operating Temperature
- Fast Switching
- Ease of Parallelizing
- Simple Drive Requirements
- Lead (Pb)-free Available


RoHS*
COMPLIANT

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION

Package	TO-220
Lead (Pb)-free	IRF9Z24PbF SiHF9Z24-E3
SnPb	IRF9Z24 SiHF9Z24

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	- 60	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current	I _D	- 11	A
		- 7.7	
Pulsed Drain Current ^a	I _{DM}	- 44	
Linear Derating Factor		0.40	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	240	mJ
Repetitive Avalanche Current ^a	I _{AR}	- 11	A
Repetitive Avalanche Energy ^a	E _{AR}	6.0	mJ
Maximum Power Dissipation	P _D	60	W
Peak Diode Recovery dV/dt ^c	dV/dt	- 4.5	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = - 25 V, starting T_J = 25 °C, L = 2.3 mH, R_G = 25 Ω, I_{AS} = - 11 A (see fig. 12).

c. I_{SD} ≤ - 11 A, dI/dt ≤ 140 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 175 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

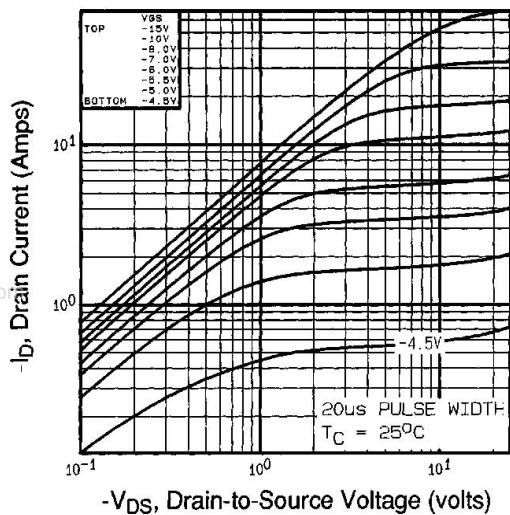
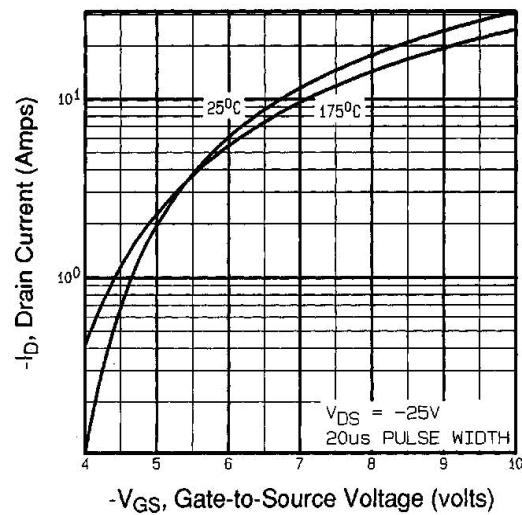
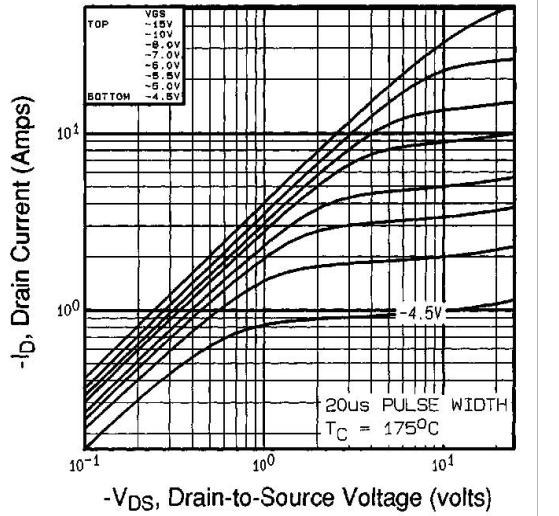
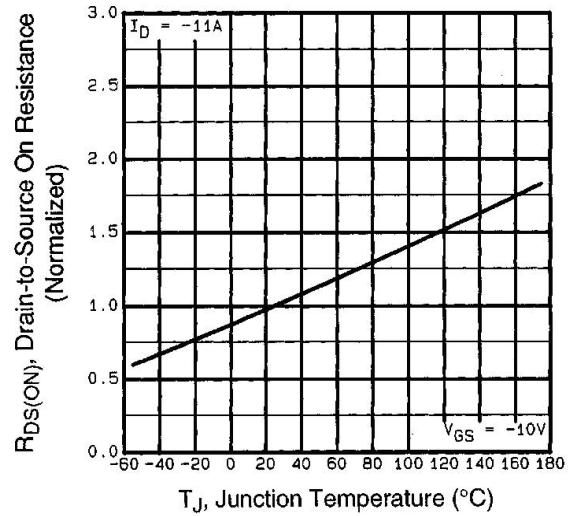
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	62	°C/W
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.50	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	2.5	

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$, $I_D = -250 \mu\text{A}$		- 60	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = -1 \text{ mA}$		-	- 0.056	-	$\text{V}/^\circ\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = -250 \mu\text{A}$		- 2.0	-	- 4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -60 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	- 100	μA	
		$V_{DS} = -48 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 150^\circ\text{C}$		-	-	- 500		
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	$V_{GS} = -10 \text{ V}$	$I_D = -6.6 \text{ A}^b$	-	-	0.28	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = -25 \text{ V}$, $I_D = -6.6 \text{ A}^b$		1.4	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = -25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	570	-	pF	
Output Capacitance	C_{oss}			-	360	-		
Reverse Transfer Capacitance	C_{rss}			-	65	-		
Total Gate Charge	Q_g	$V_{GS} = -10 \text{ V}$	$I_D = -11 \text{ A}$, $V_{DS} = -48 \text{ V}$, see fig. 6 and 13 ^b	-	-	19	nC	
Gate-Source Charge	Q_{gs}			-	-	5.4		
Gate-Drain Charge	Q_{gd}			-	-	11		
Turn-On Delay Time	$t_{d(\text{on})}$			-	13	-		
Rise Time	t_r	$V_{DD} = -30 \text{ V}$, $I_D = -11 \text{ A}$, $R_G = 18 \Omega$, $R_D = 2.5 \Omega$, see fig. 10 ^b		-	68	-	ns	
Turn-Off Delay Time	$t_{d(\text{off})}$			-	15	-		
Fall Time	t_f			-	29	-		
Internal Drain Inductance	L_D			-	4.5	-	nH	
Internal Source Inductance	L_S	Between lead, 6 mm (0.25") from package and center of die contact		-	7.5	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 11	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	- 44		
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}$, $I_S = -11 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	- 6.3	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_F = -11 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	100	200	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	0.32	0.64	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics, $T_C = 25\text{ }^\circ\text{C}$

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics, $T_C = 175\text{ }^\circ\text{C}$

Fig. 4 - Normalized On-Resistance vs. Temperature

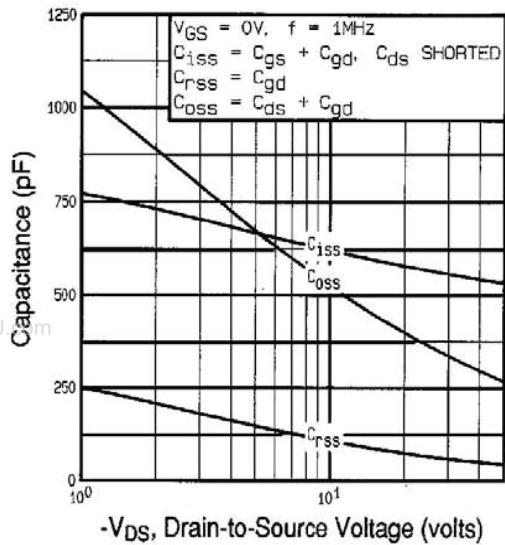


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

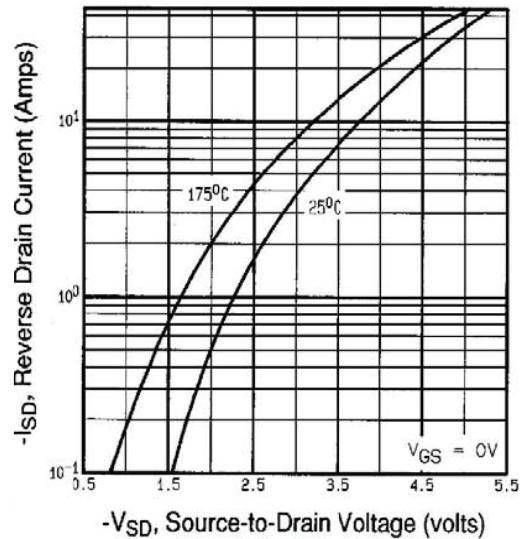


Fig. 7 - Typical Source-Drain Diode Forward Voltage

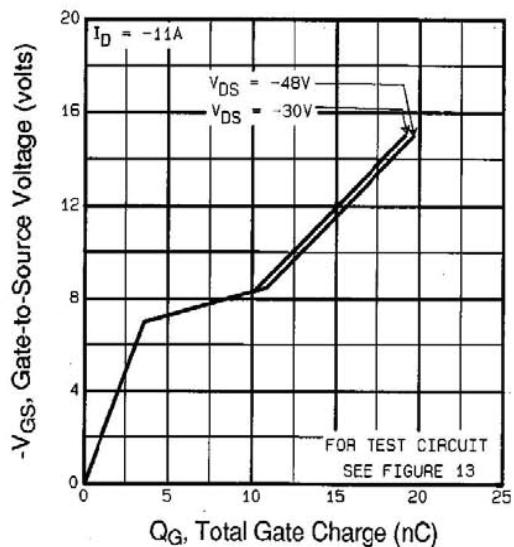


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

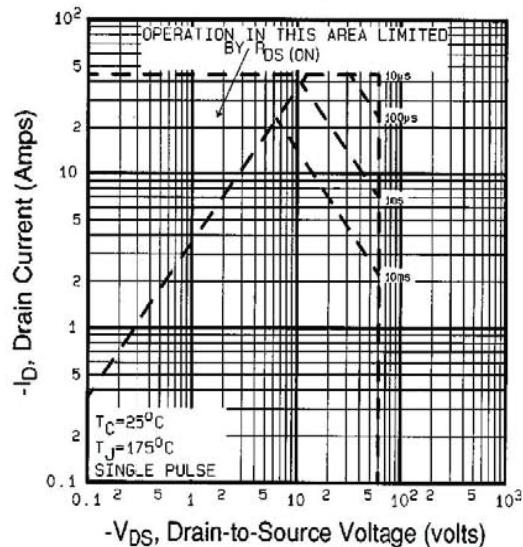
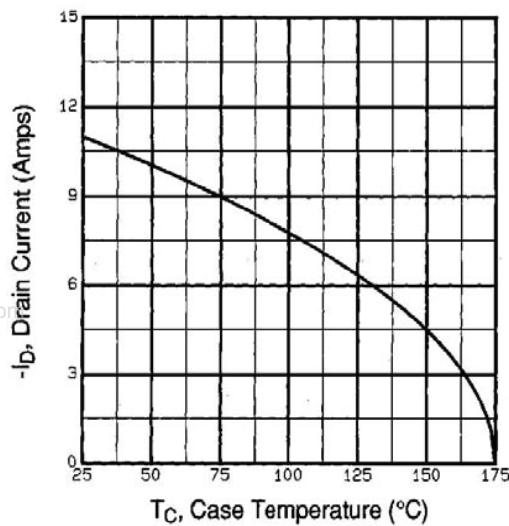
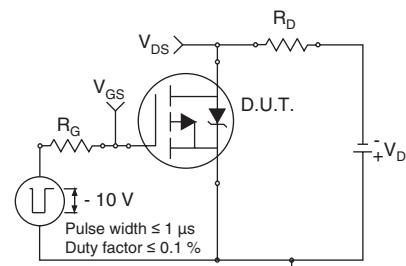
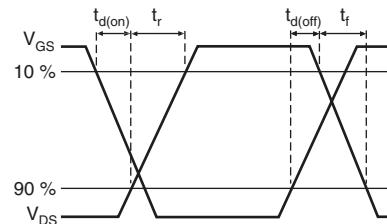
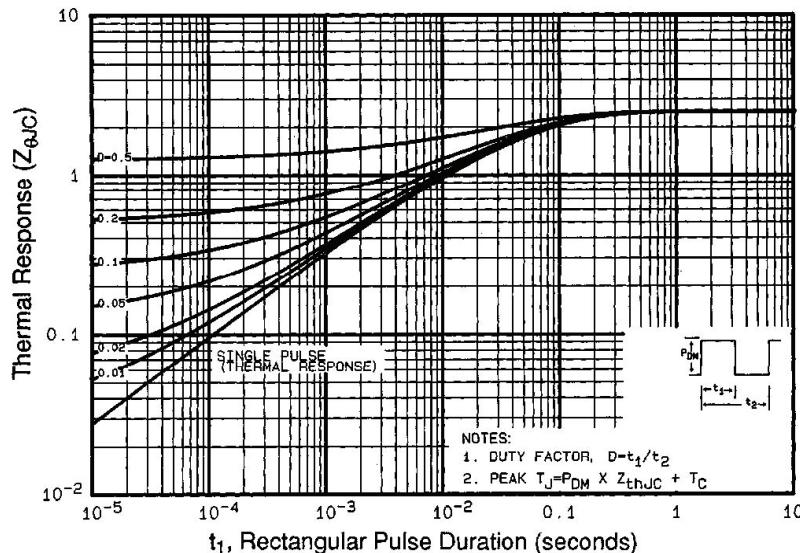
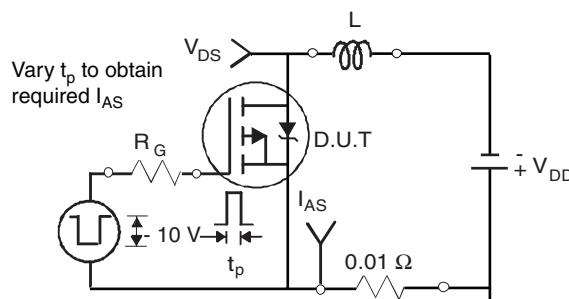
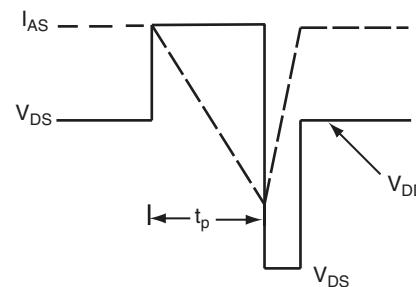


Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10a - Switching Time Test Circuit

Fig. 10b - Switching Time Waveforms

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

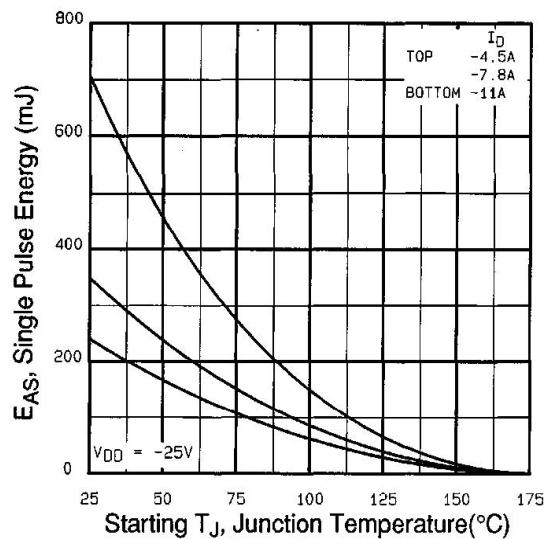


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

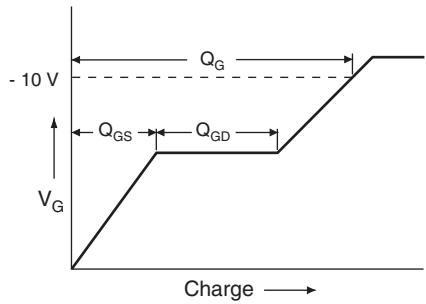


Fig. 13a - Basic Gate Charge Waveform

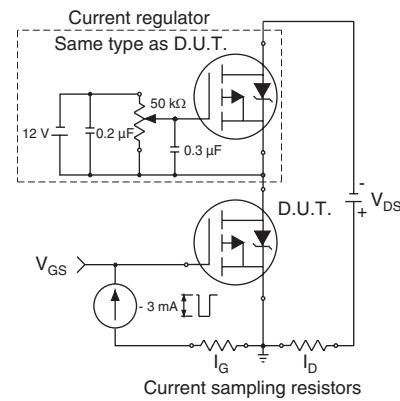
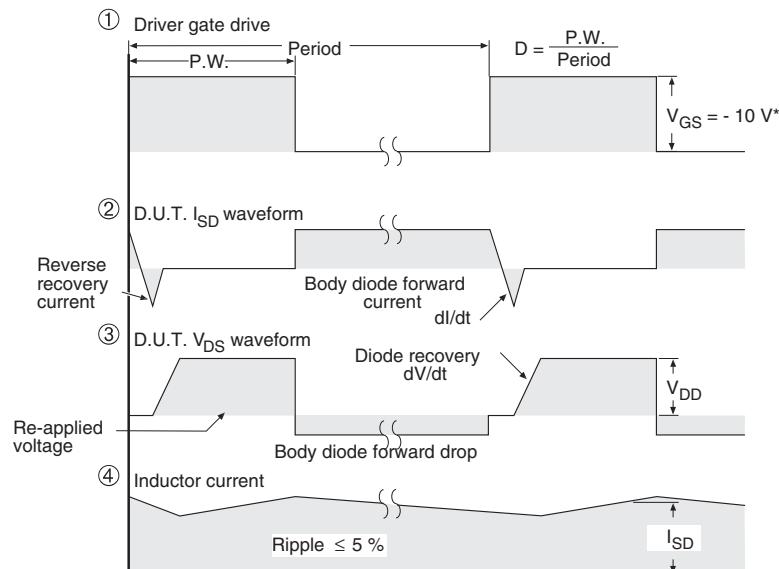
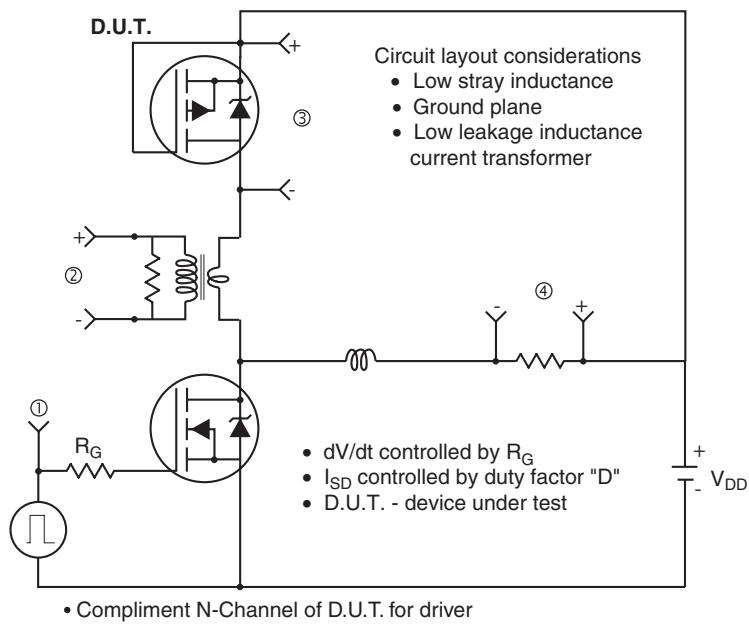


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = -5$ V for logic level and -3 V drive devices

Fig. 14 - For P-Channel

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